

Appl. No. 10/672,655
Amdt. dated December 30, 2004
Reply to Office action of July 13, 2004

Amendments to the Specification:

In the Abstract, please replace the paragraph beginning at line 4 with the following amended paragraph:

A probe assembly suitable for making test measurements using test signals having high currents. The disclosed probe assembly provides for a test signal exhibiting relatively low inductance when compared to existing probe assemblies by preferably reducing the electrical path distance between the test instrumentation and the electrical device being tested.